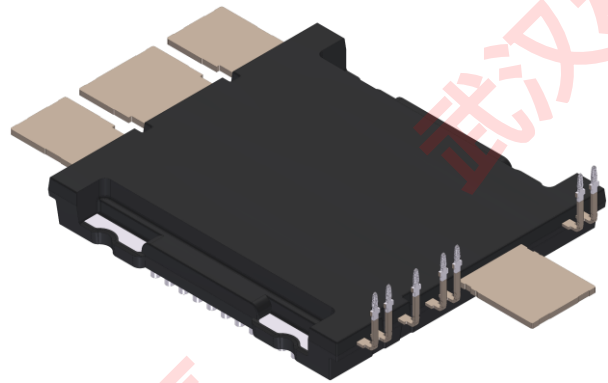


5SFG 1150B120001

RoadPak SiC phase leg module 1200 V, 1200 A*

- $V_{DSS} = 1200 \text{ V}$
- $I_D = 2 \times 1200 \text{ A}^*$
- Molded package optimized for e-Mobility application
- Pin-fin structure for lowest thermal resistance
- Lowest losses thanks to Silicon Carbide chip set
- Main terminals with holes for screw connection or without holes for welding



*Current rating based on chip rating times number of chips

Maximum rated values ¹⁾

Parameter	Symbol	Conditions	Min.	Max.	Unit
Drain-source voltage	V_{DS}	$V_{GS} = 0 \text{ V}$, $T_{vj} \geq -40 \text{ }^\circ\text{C}$		1200	V
DC drain current	I_D	$T_{Cool} = 65 \text{ }^\circ\text{C}$, $T_{vj} = 175 \text{ }^\circ\text{C}$		740	A
Peak drain current	I_{DM}	$t_p = 1 \text{ ms}$, limited by T_{jmax}		1800	A
Recommended static gate - source voltage	$V_{GS,DC}$		-4	15	V
Max gate - source voltage ²⁾	$V_{GS,max,DC}$		-8	19	V
DC reverse drain current (body diode)	I_{DR}	$V_{GS} = -4 \text{ V}$, $T_{Cool} = 65 \text{ }^\circ\text{C}$, $T_{vj} = 175 \text{ }^\circ\text{C}$		300	A
Peak reverse drain current (body diode)	I_{DRM}	$V_{GS} = -4 \text{ V}$, $t_p = 1 \text{ ms}$		1800	A
Surge source current (body diode)	I_{SSM}	$V_{GS} = -4 \text{ V}$, $T_{vj} = 175 \text{ }^\circ\text{C}$, $t_p = 10 \text{ ms}$, half-sinewave		3000	A
DC reverse drain current (channel open)	I_{DRS}	$V_{GS} = 15 \text{ V}$, $T_{Cool} = 65 \text{ }^\circ\text{C}$, $T_{vj} = 175 \text{ }^\circ\text{C}$		740	A
Surge source current (channel open)	I_{SSX}	$V_{GS} = 15 \text{ V}$, $T_{vj} = 175 \text{ }^\circ\text{C}$, $t_p = 10 \text{ ms}$, half-sinewave		1700	A
MOSFET short circuit SOA	t_{psc}	$V_{DD} = 850 \text{ V}$, $V_{GS} = -4/15 \text{ V}$, $T_{vj} \leq 175 \text{ }^\circ\text{C}$		1.5	μs
Isolation voltage	V_{isol}	1 min, $f = 50 \text{ Hz}$		3300	V
Junction temperature	T_{vj}			175	$^\circ\text{C}$
Junction operating temperature	$T_{vj(op)}$		-40	175	$^\circ\text{C}$
Storage temperature	T_{stg}		-40	150	$^\circ\text{C}$
Mounting torque	M_s	Module to cooler with M4 screws	2.6	3.1	Nm

¹⁾ Maximum rated values indicate limits beyond which damage to the device may occur per IEC 60747

²⁾ Based on chip capability

MOSFET characteristic values ³⁾

Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit
Drain-source breakdown voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{ V}, I_D = 1\text{ mA}$	$T_{vj} = 175\text{ °C}$	1200		V
			$T_{vj} = 25\text{ °C}$	1200		V
			$T_{vj} = -40\text{ °C}$	1200		V
Static drain-source on-state resistance ⁴⁾	$R_{DS(on)}$	$I_D = 813\text{ A}, V_{GS} = 15\text{ V}$	$T_{vj} = 25\text{ °C}$	1.4	1.7	mΩ
			$T_{vj} = 175\text{ °C}$	2.5	2.96	mΩ
Zero gate voltage drain current	I_{DSS}	$V_{DS} = 1200\text{ V}, V_{GS} = 0\text{ V}$	$T_{vj} = 25\text{ °C}$	10	350	μA
			$T_{vj} = 175\text{ °C}$	20	500	μA
Gate-source leakage current	I_{GSS}	$V_{DS} = 0\text{ V}, V_{GS} = 15\text{ V}, T_{vj} = 25\text{ °C}$			500	nA
Gate threshold voltage ²⁾	$V_{GS(th)}$	$I_D = 220\text{ mA}, V_{DS} = V_{GS}, T_{vj} = 25\text{ °C}$	1.8	2.5	3.6	V
Gate charge	Q_G	$I_D = 1000\text{ A}, V_{DS} = 800\text{ V}, V_{GS} = -4\text{ V} \dots +15\text{ V}$		2.5		μC
Input capacitance ²⁾	C_{ISS}	$V_{DS} = 1000\text{ V}, V_{GS} = 0\text{ V}, T_{vj} = 25\text{ °C}, f = 100\text{ kHz}$		72		nF
Internal gate resistance ²⁾	R_{Gint}	$f = 1\text{ MHz}, V_{AC} = 25\text{ mV}, \text{ per switch}$		0.63		Ω
Turn-on delay time	$t_{d(on)}$	$V_{DD} = 800\text{ V}, I_D = 1000\text{ A}, R_G = 1\text{ Ω}, V_{GS} = -4 / +15\text{ V}, L_\sigma = 10\text{ nH}, \text{ inductive load}$	$T_{vj} = 25\text{ °C}$	160		ns
			$T_{vj} = 175\text{ °C}$	155		ns
Rise time	t_r	$V_{DD} = 800\text{ V}, I_D = 1000\text{ A}, R_G = 1\text{ Ω}, V_{GS} = -4 / +15\text{ V}, L_\sigma = 10\text{ nH}, \text{ inductive load}$	$T_{vj} = 25\text{ °C}$	60		ns
			$T_{vj} = 175\text{ °C}$	55		ns
Turn-off delay time	$t_{d(off)}$	$V_{DD} = 800\text{ V}, I_D = 1000\text{ A}, R_G = 2.2\text{ Ω}, V_{GS} = -4 / +15\text{ V}, L_\sigma = 10\text{ nH}, \text{ inductive load}$	$T_{vj} = 25\text{ °C}$	510		ns
			$T_{vj} = 175\text{ °C}$	530		ns
Fall time	t_f	$V_{DD} = 800\text{ V}, I_D = 1000\text{ A}, R_G = 2.2\text{ Ω}, V_{GS} = -4 / +15\text{ V}, L_\sigma = 10\text{ nH}, \text{ inductive load}$	$T_{vj} = 25\text{ °C}$	68		ns
			$T_{vj} = 175\text{ °C}$	70		ns
Turn-on switching energy	E_{on}	$V_{DD} = 800\text{ V}, I_D = 1000\text{ A}, R_G = 1\text{ Ω}, V_{GS} = -4 / +15\text{ V}, L_\sigma = 10\text{ nH}, \text{ inductive load}$	$T_{vj} = 25\text{ °C}$	45		mJ
			$T_{vj} = 175\text{ °C}$	40		mJ
Turn-off switching energy	E_{off}	$V_{DD} = 800\text{ V}, I_D = 1000\text{ A}, R_G = 2.2\text{ Ω}, V_{GS} = -4 / +15\text{ V}, L_\sigma = 10\text{ nH}, \text{ inductive load}$	$T_{vj} = 25\text{ °C}$	72		mJ
			$T_{vj} = 175\text{ °C}$	70		mJ
Short circuit current	I_{SC}	$t_{on} \leq 1.5\text{ μs}, V_{GS} = 15\text{ V}, V_{DD} = 850\text{ V}, V_{DSM\ CHIP} \leq 1200\text{ V}$	$T_{vj} = 175\text{ °C}$	13		kA

²⁾ Based on chip capability

³⁾ Characteristic values according to IEC 60747 – 8

⁴⁾ $R_{DS(on)}$ is given at chip level

Body diode characteristic values ⁵⁾

Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit
Diode forward voltage ^{2) 6)}	V _{SD}	I _S = 406 A, V _{GS} = -4 V	T _{vj} = 25 °C	4.9		V
			T _{vj} = 175 °C	4.4		V
Reverse recovery current	I _{rr}		T _{vj} = 25 °C	180		A
			T _{vj} = 175 °C	500		A
Recovered charge	Q _{rr}	V _{DS} = 800 V, I _{SD} = 1000 A, V _{GS} = -4 / +15 V, R _G = 1 Ω	T _{vj} = 25 °C	15		μC
			T _{vj} = 175 °C	32		μC
Reverse recovery time	t _{rr}	di/dt = 23 kA/μs, L _σ = 10 nH, inductive load	T _{vj} = 25 °C	10		ns
			T _{vj} = 175 °C	90		ns
Reverse recovery energy	E _{rec}		T _{vj} = 25 °C	5		mJ
			T _{vj} = 175 °C	14		mJ

²⁾ Based on chip capability

⁵⁾ Characteristic values according to IEC 60747 – 2

⁶⁾ Forward voltage is given at chip level

Package properties ⁷⁾

Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit
Thermal resistance ⁸⁾ junction to fluid	R _{th(j-f)}	T _{in} = 65 °C, Coolant: 50% glycol/ 50% water, per switch, 10 L/min, dp < 120 mbar		82	86	K/kW
Comparative tracking index	CTI		400			V
Module stray inductance	L _σ			5		nH
Resistance, terminal-chip	R _{DD+SS'}		T _c = 25 °C	0.117		mΩ
			T _c = 150 °C	0.227		mΩ

⁷⁾ Package and mechanical properties according to IEC 60747 – 1

⁸⁾ See Fig. 16 .. 23 for more information

NTC Thermistor

Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit
Rated resistance	R ₂₅	T _c =25 °C		4700		Ω
R100	R ₁₀₀	T _c =100 °C		457.9		Ω
B-value	B _{25/85}	R = R ₂₅ exp [B _{25/85} (1/T – 1/(298.15K))]		3435		K

Mechanical properties ⁷⁾

Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit
Dimensions	L	AC terminal to DC terminal		110		mm
	W	Mold width		69		mm
	H	Baseplate cooler surface to middle of PCB/pressfit		17.35		mm
Clearance distance in air	d _a	According to IEC 60664-1	Term. to Base:	6.9		mm
			Term. to Term.:	3.3		mm
Surface creepage distance	d _s	According to IEC 60664-1	Term. to Base:	8.5		mm
			Term. to Term.:	8		mm
Mass	m			310		g

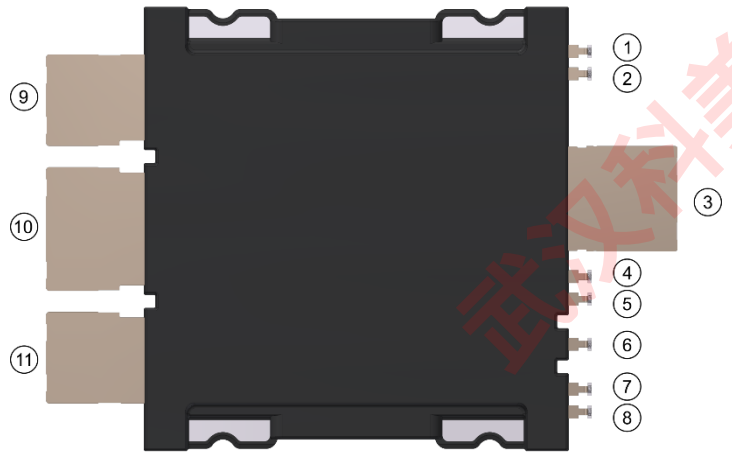
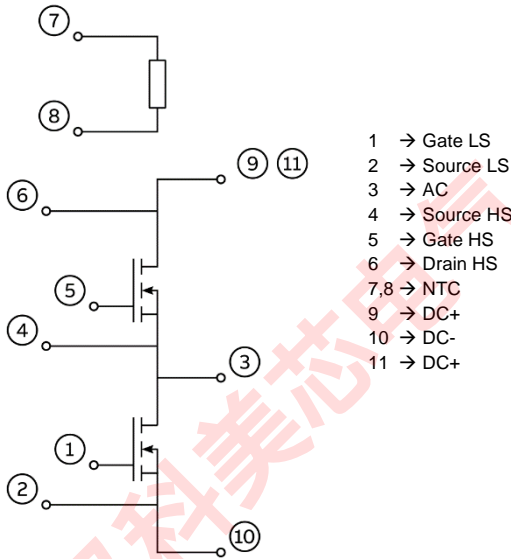
⁷⁾ Package and mechanical properties according to IEC 60747 – 1

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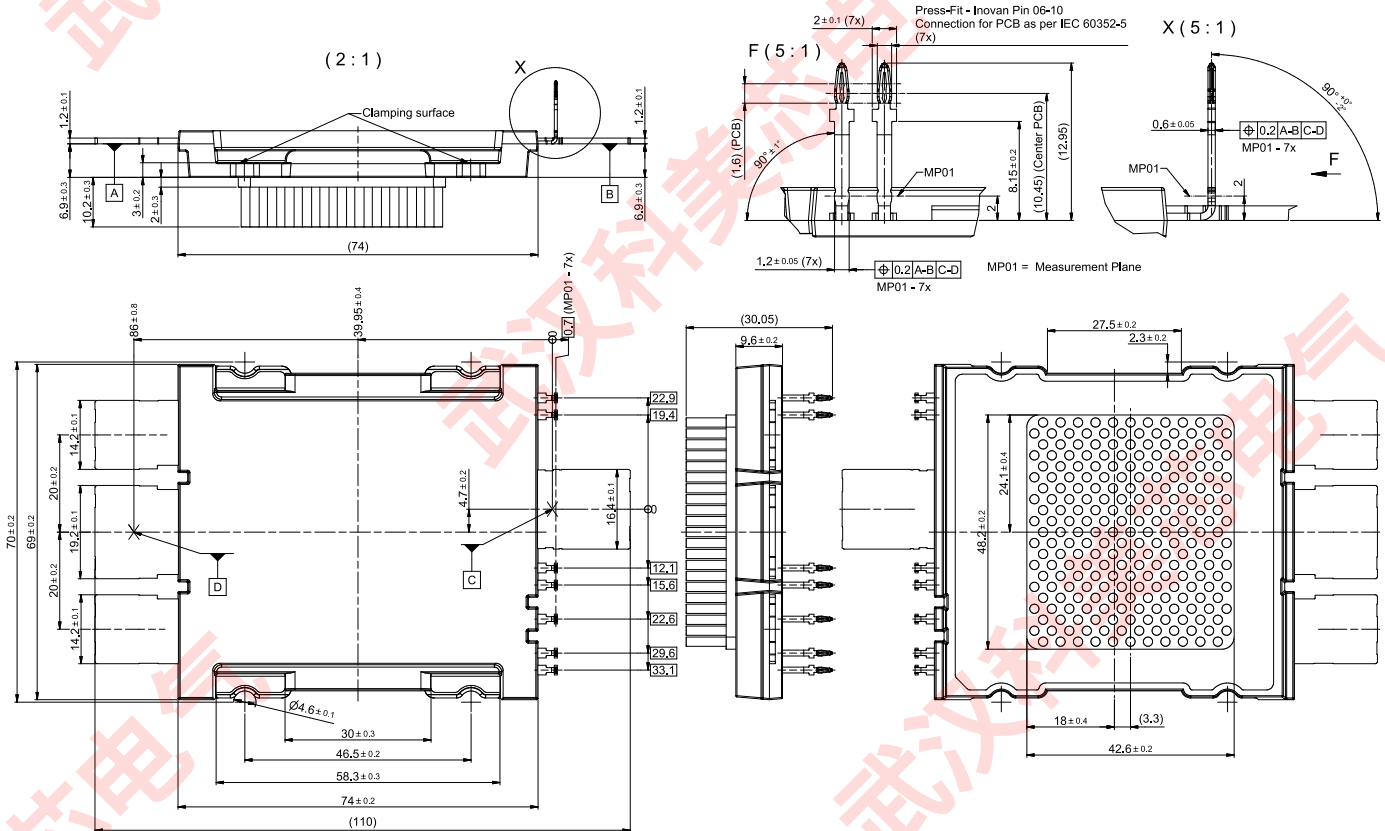
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Electrical configuration



Mechanical drawing



Note: all dimensions are shown in millimeters

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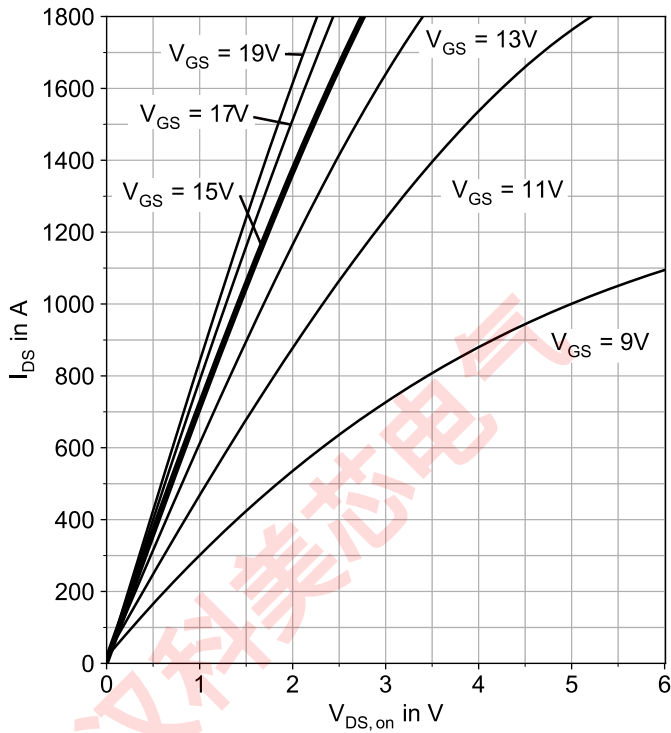


Fig. 1 Typical output characteristics

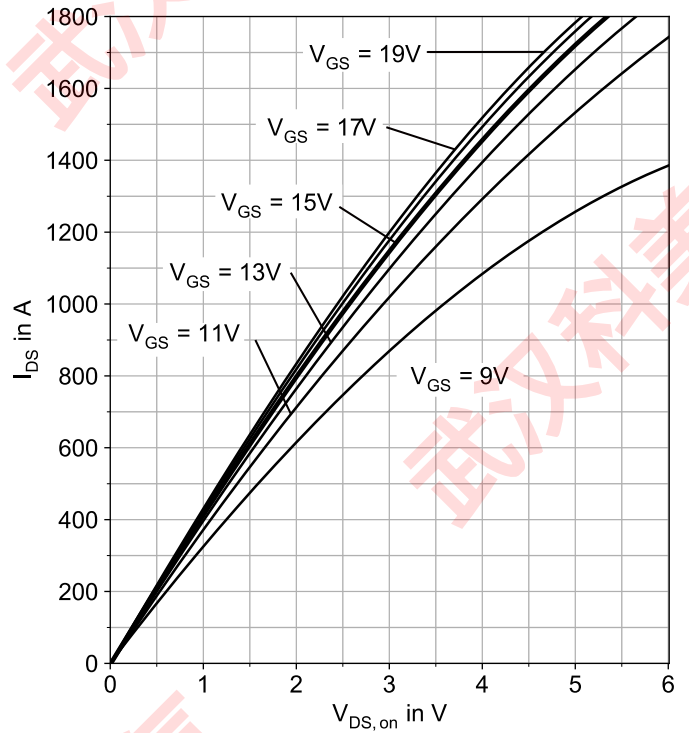


Fig. 2 Typical output characteristics

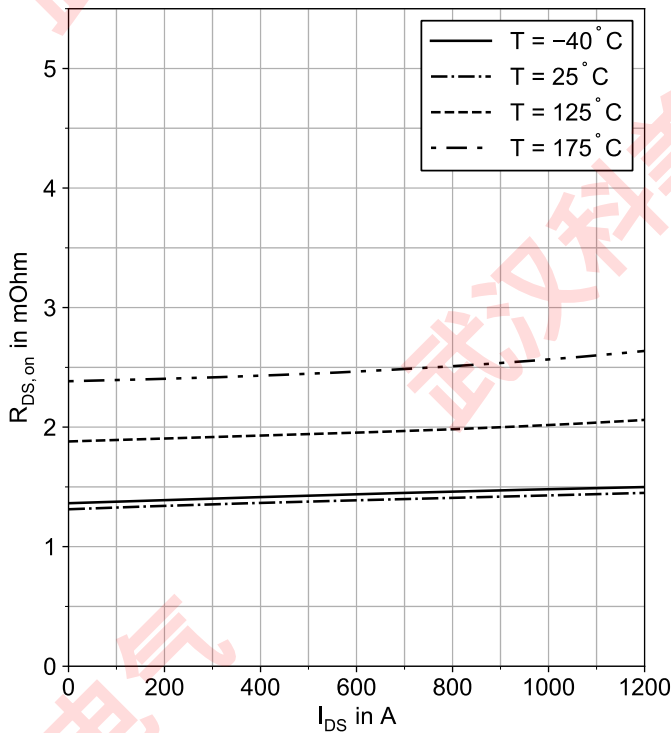


Fig. 3 Typical on-state resistance vs. drain current for various junction temperatures

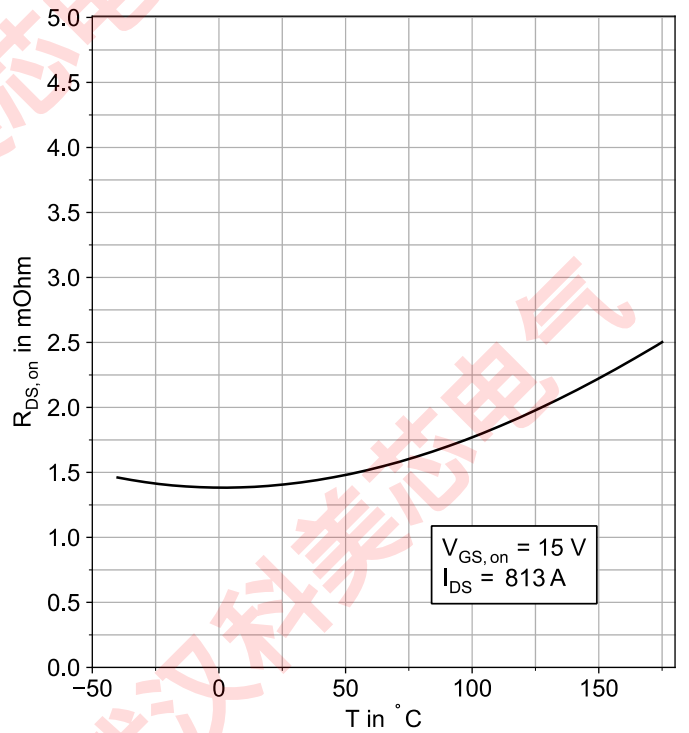


Fig. 4 Typical on-state resistance vs. temperature

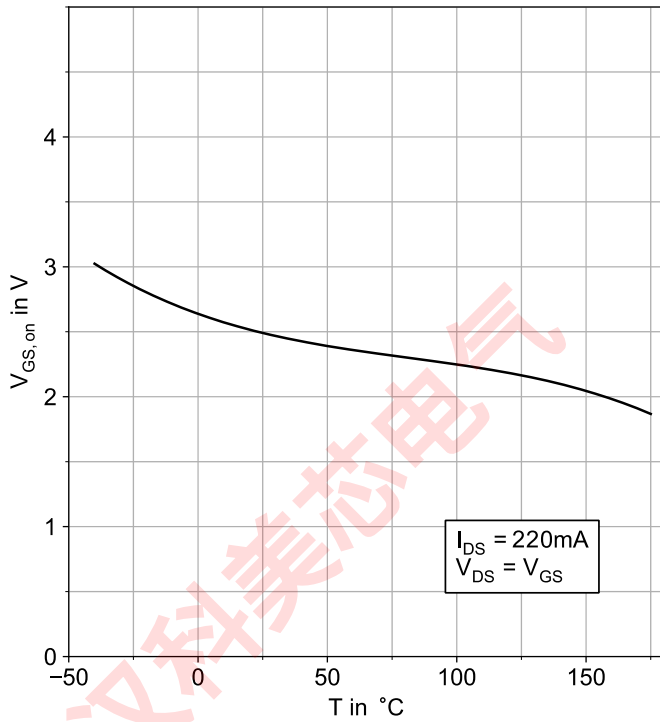


Fig. 5 Threshold voltage vs junction temperature

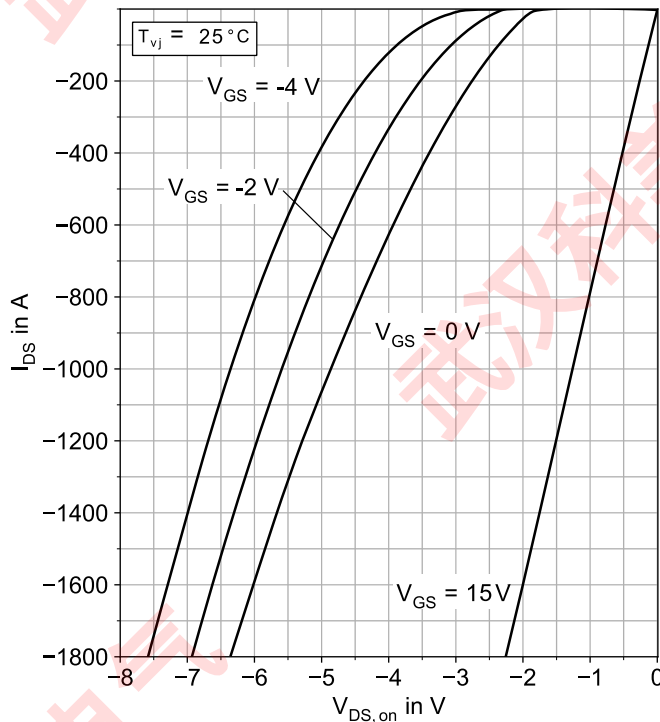


Fig. 6 Typical 3rd quadrant characteristics vs drain current

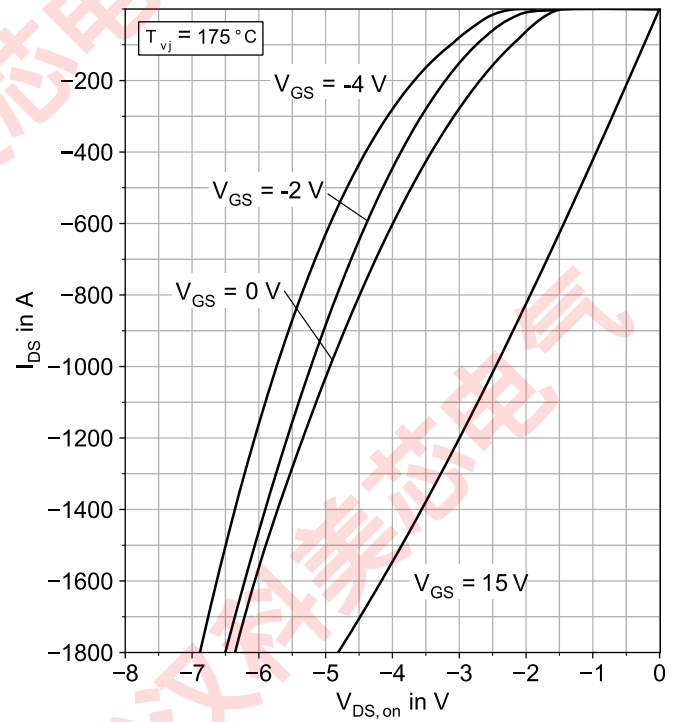


Fig. 7 Typical 3rd quadrant characteristics vs drain current

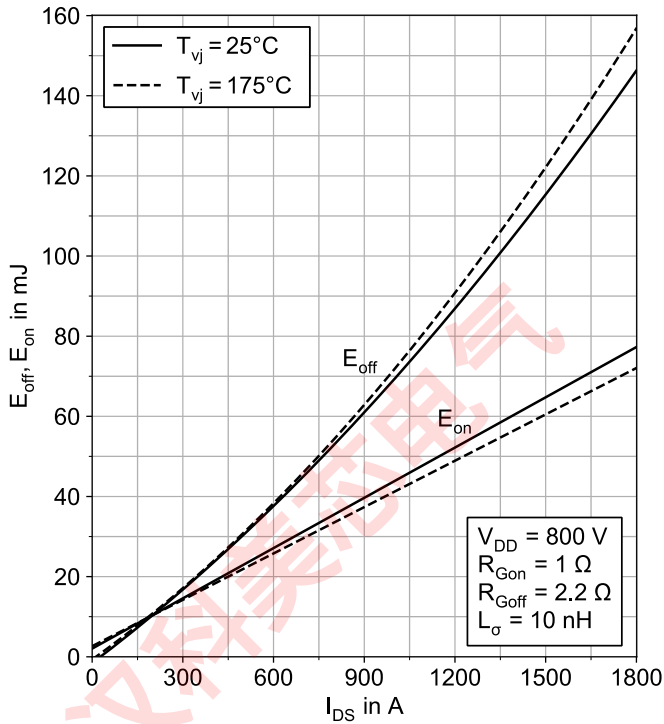


Fig. 8 Typical switching energies per pulse vs. drain current

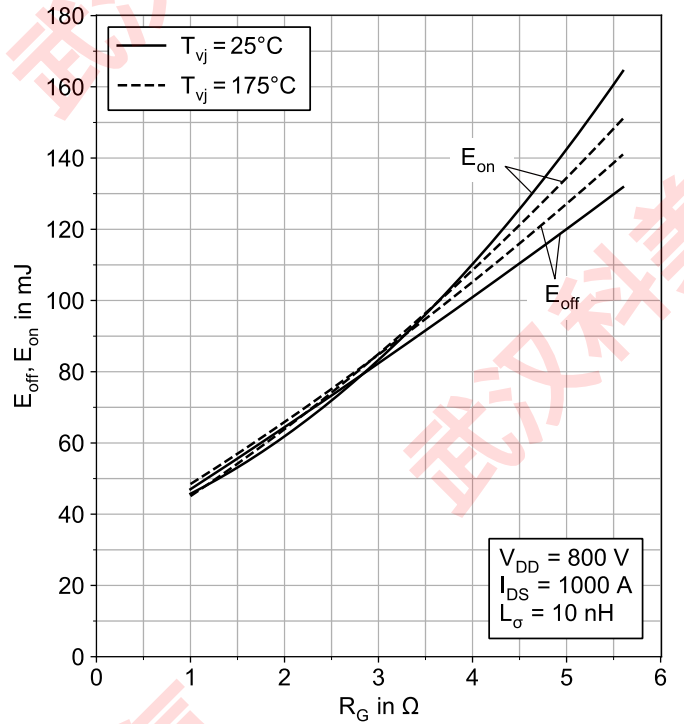


Fig. 9 Typical switching energies per pulse vs. gate resistor

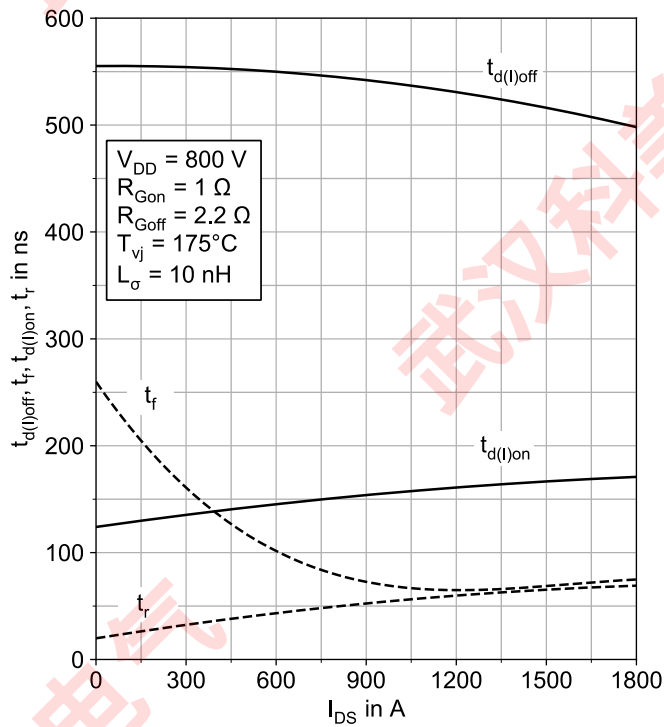


Fig. 10 Typical switching times vs. drain current

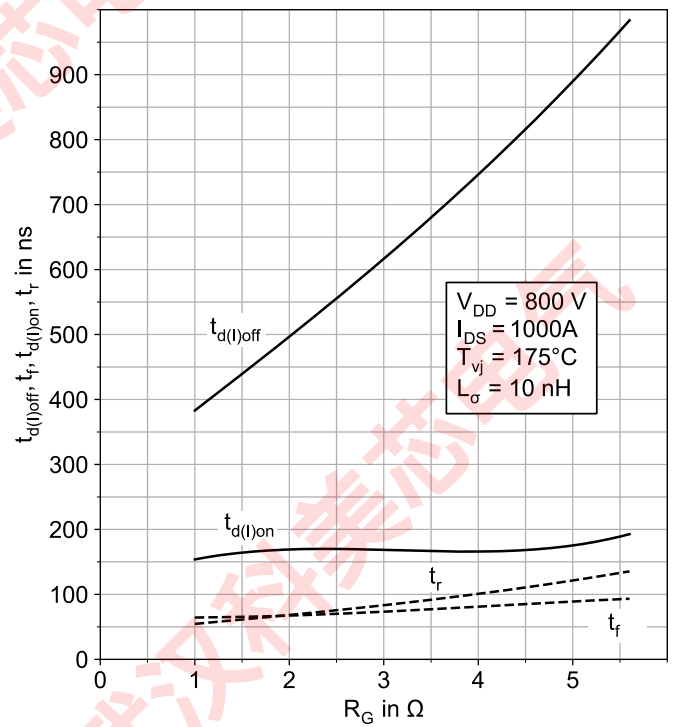


Fig. 11 Typical switching times vs. gate resistor

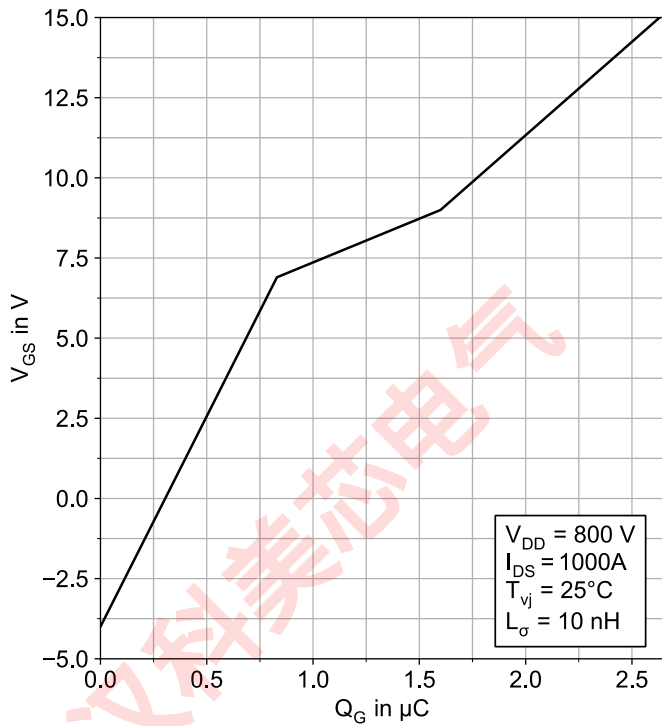


Fig. 12 Typical gate charge characteristics

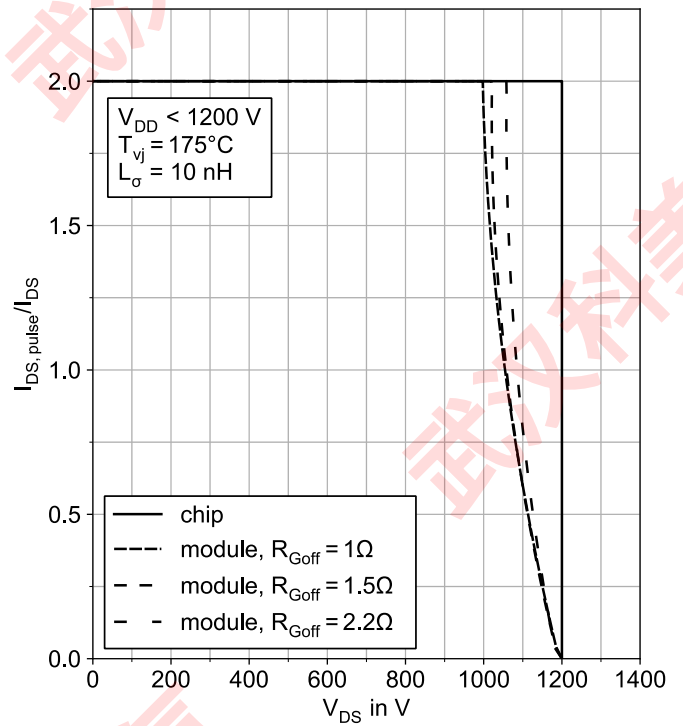


Fig. 13 Turn-off safe operating area (RBSOA)

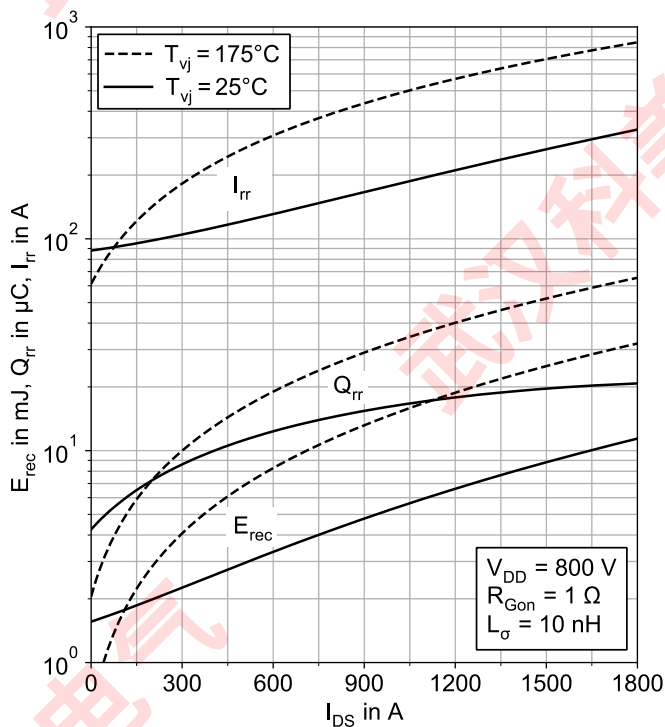


Fig. 14 Typical reverse recovery characteristics vs. forward current

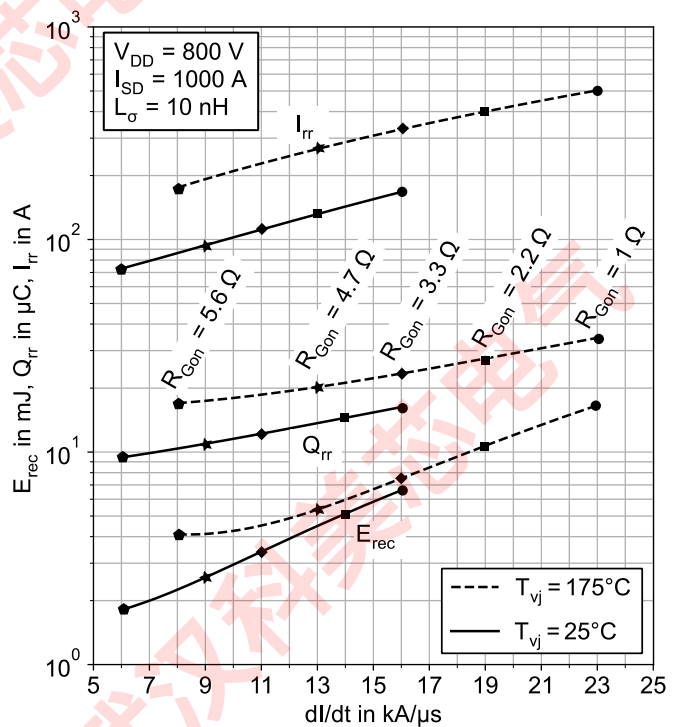


Fig. 15 Typical reverse recovery characteristics vs. di/dt

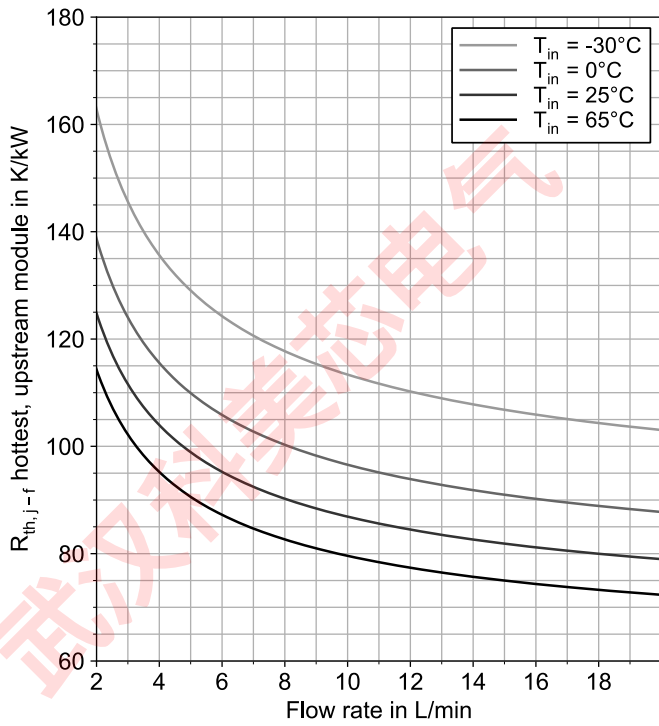
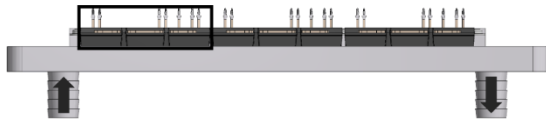


Fig. 16 Thermal resistance vs flow rate, upstream module, hottest chip

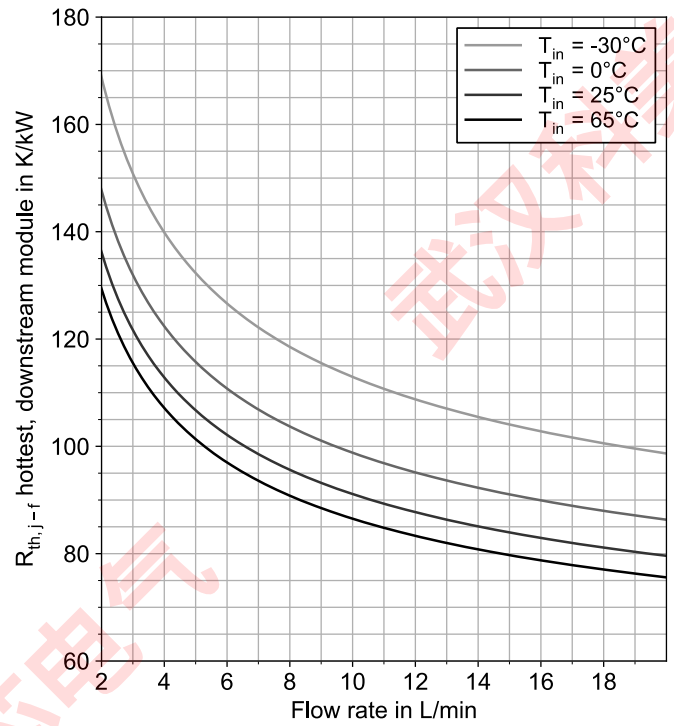
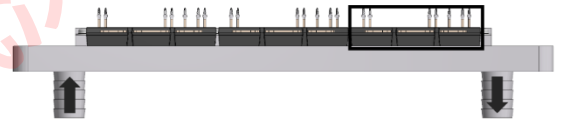


Fig. 17 Thermal resistance vs flow rate, downstream module, hottest chip

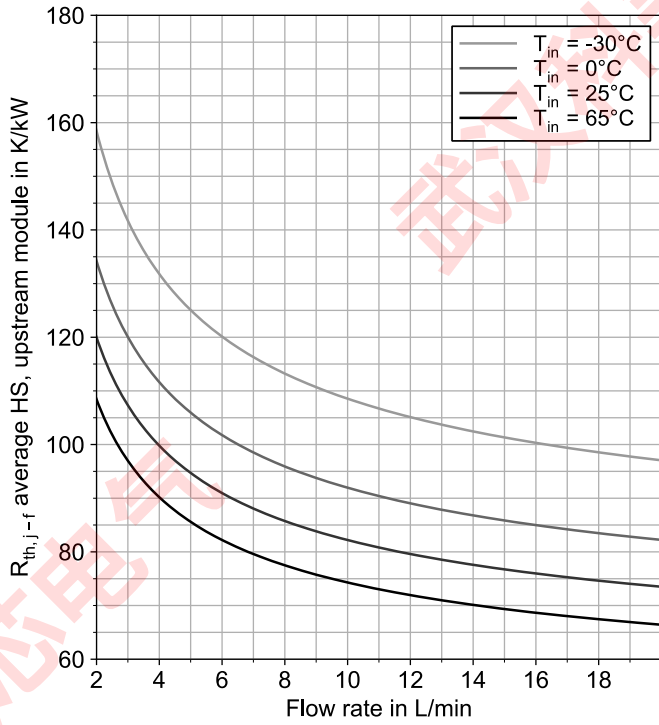


Fig. 18 Thermal resistance vs flow rate, upstream module, average

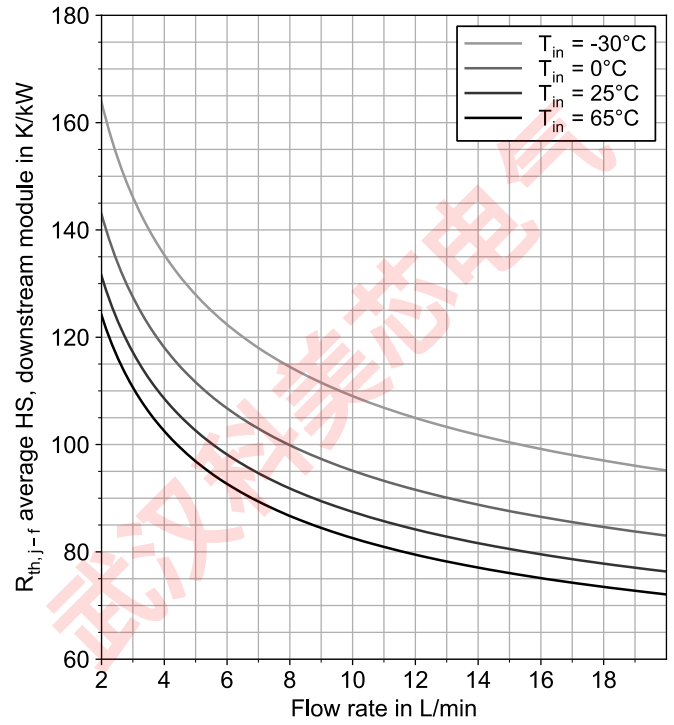


Fig. 19 Thermal resistance vs flow rate, downstream module, average

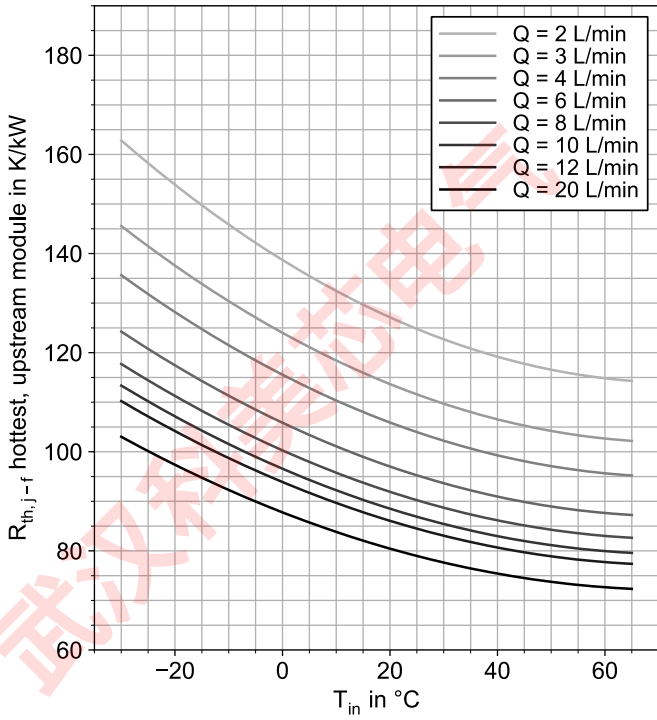
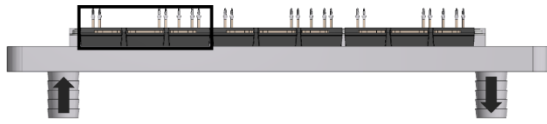


Fig. 20 Thermal resistance vs inlet temperature, upstream module, hottest chip

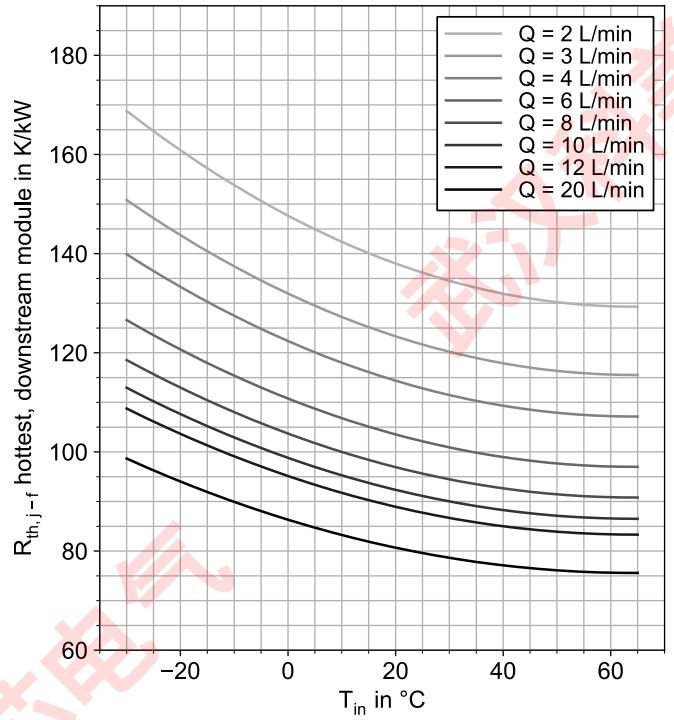
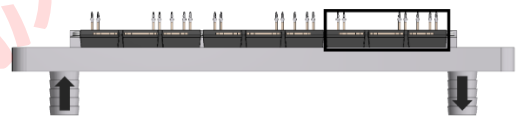


Fig. 21 Thermal resistance vs inlet temperature, downstream module, hottest chip

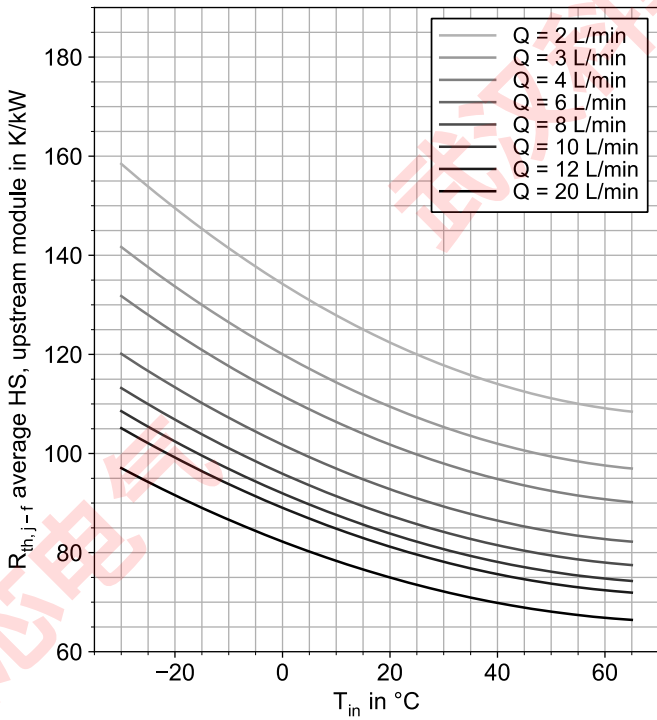


Fig. 22 Thermal resistance vs inlet temperature, upstream module, average

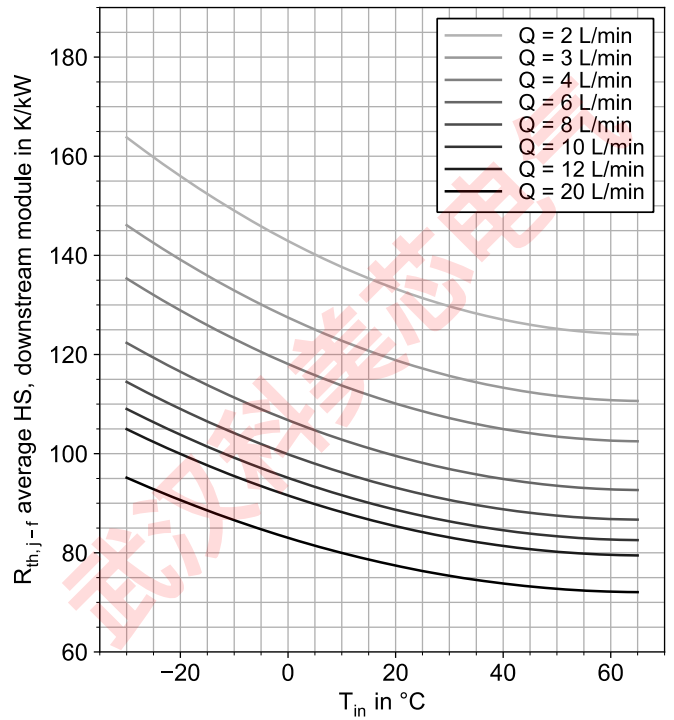


Fig. 23 Thermal resistance vs inlet temperature, downstream module, average

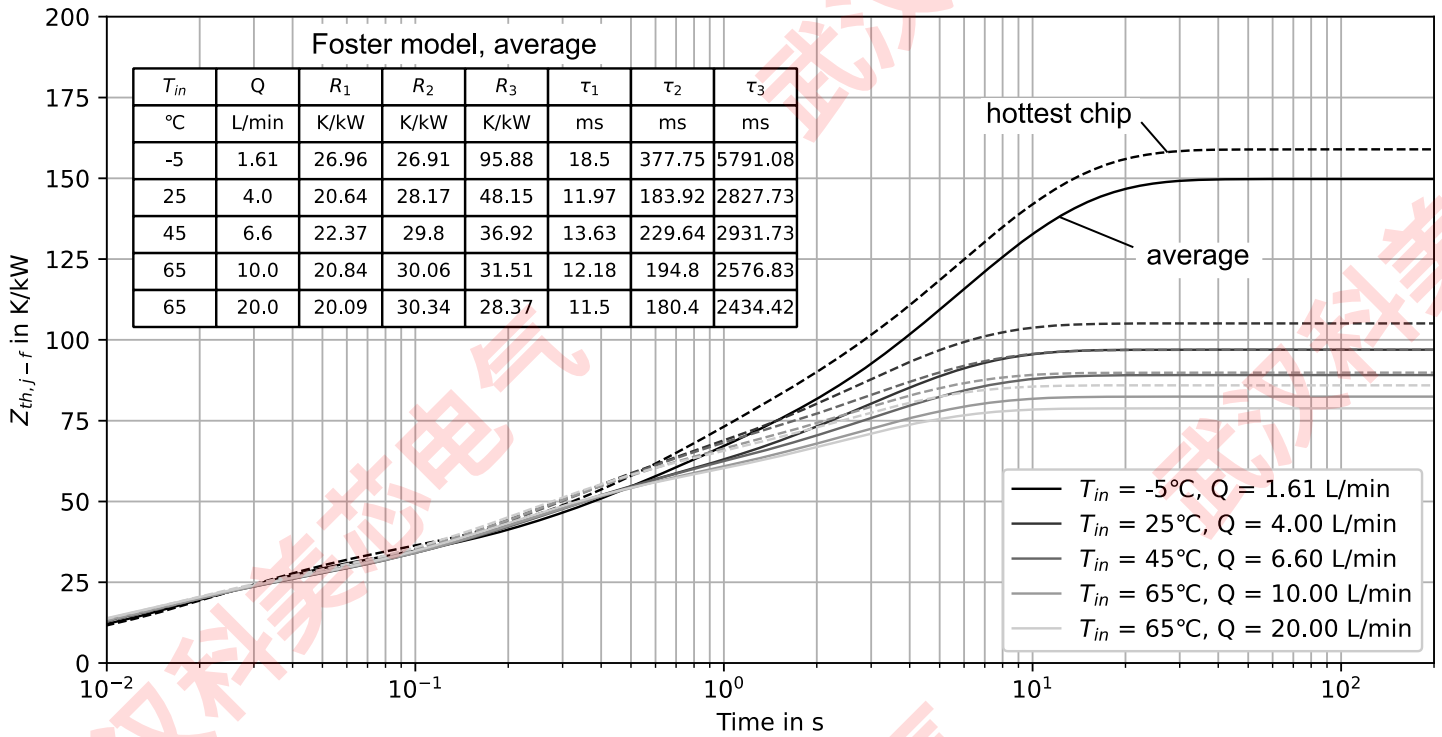


Fig. 24 Thermal impedance vs time, downstream module

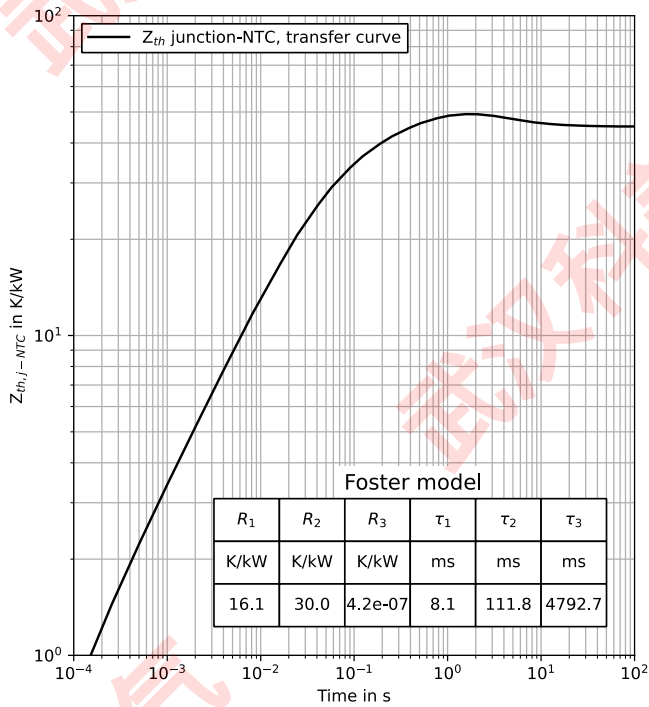


Fig. 25 Thermal impedance vs time, junction to NTC

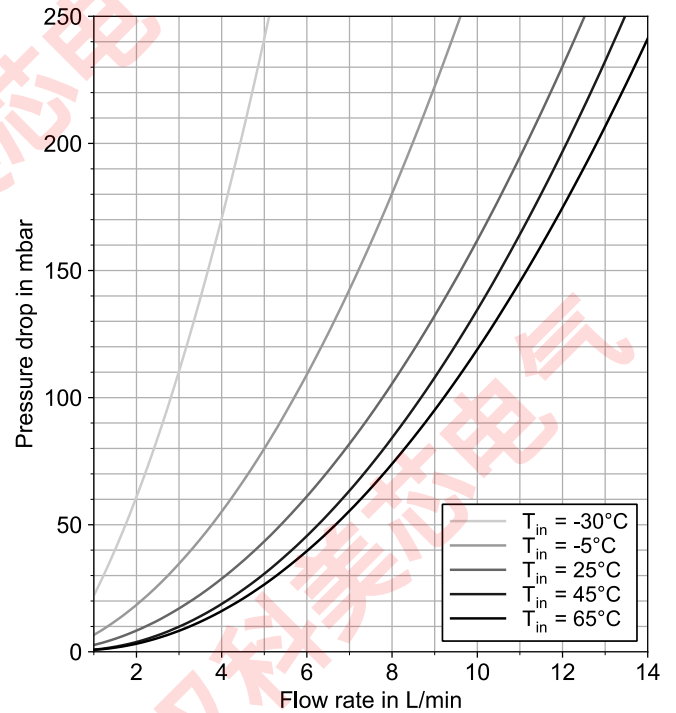


Fig. 26 Pressure drop vs flow rate